

カレントスティーリングDACの動的特性の調査

Recent studies on the dynamic behavior of current-steering DACs

東京工業大学 大学院

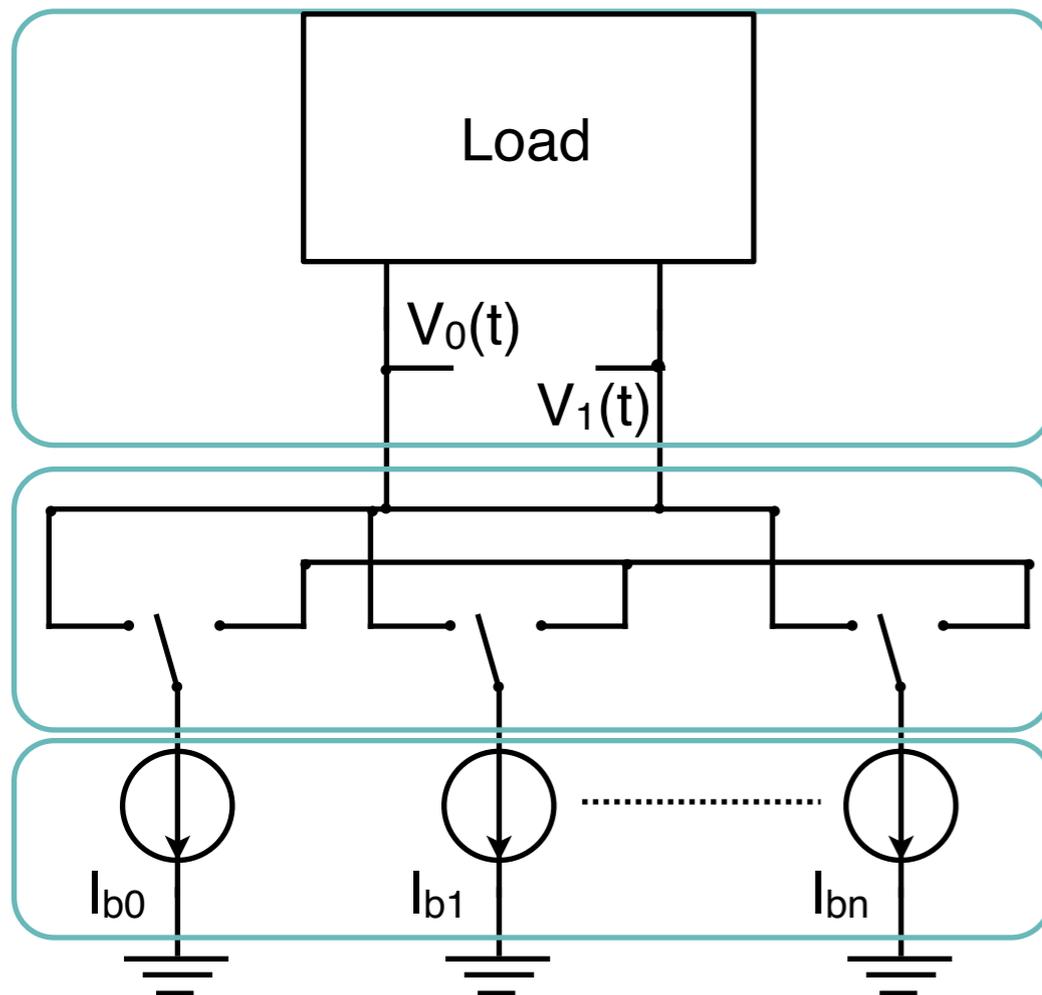
理工学研究科 電子物理工学専攻

フレイ マティアス、松澤 昭

Matthias Frey and Akira Matsuzawa

- What is a current-steering DAC?

ideal:

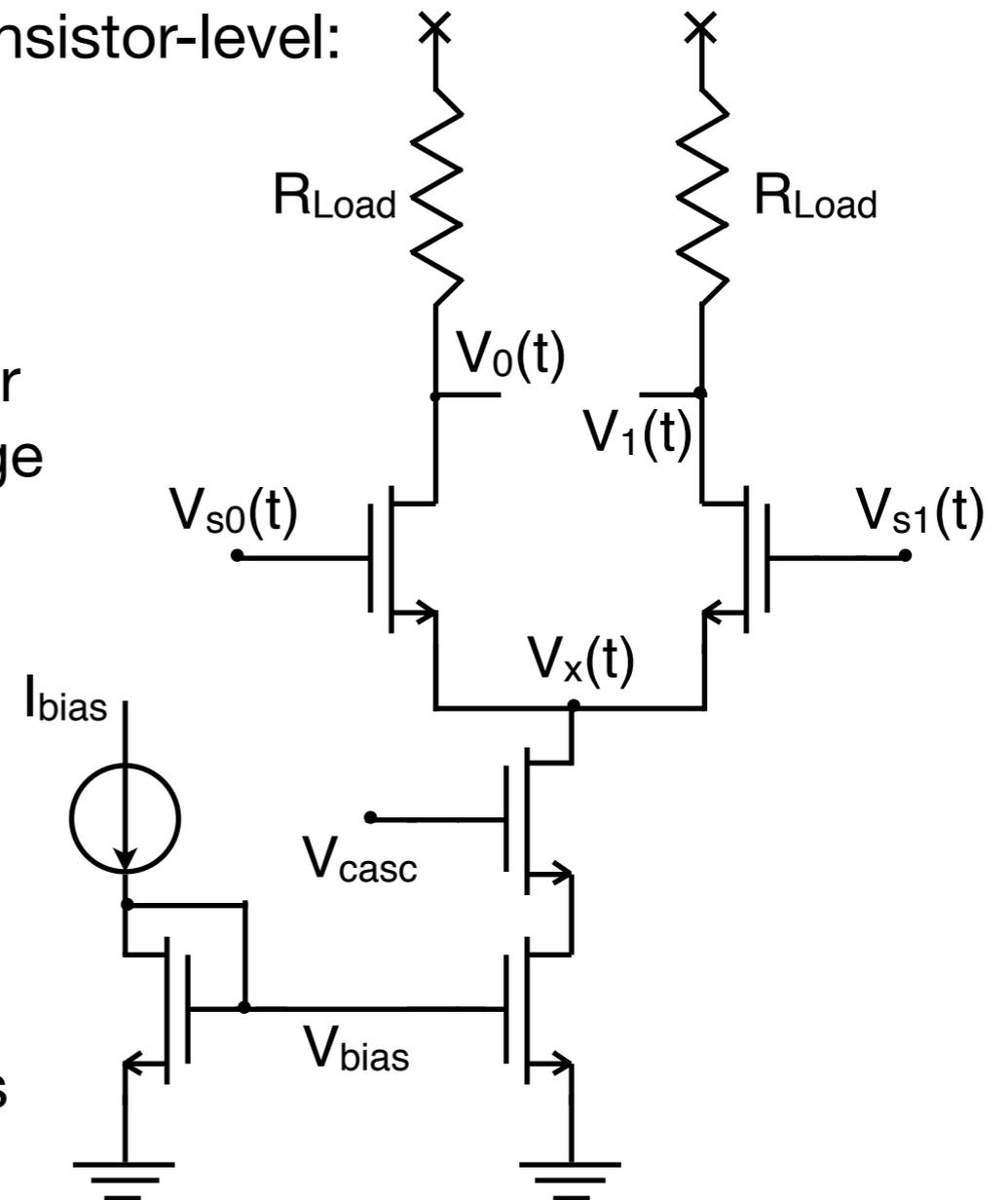


resistive load for current-to-voltage conversion

switches

scaled current sources

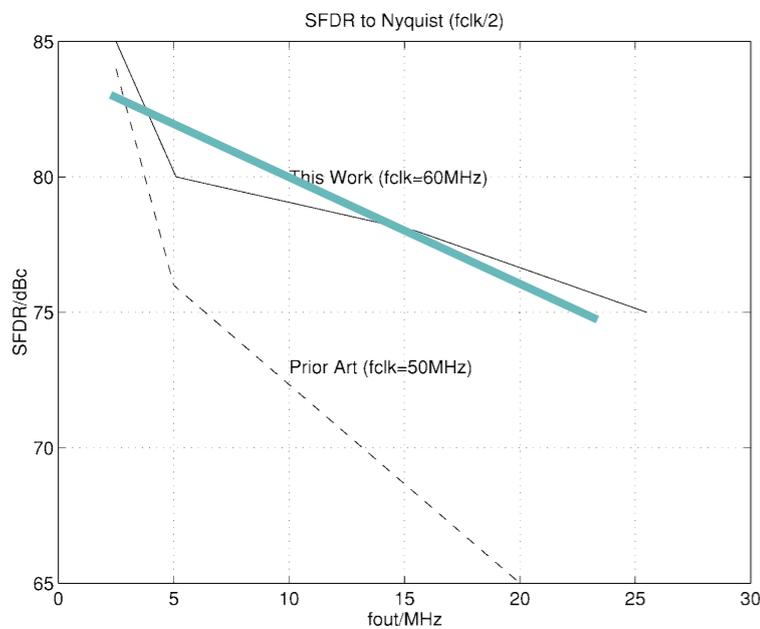
transistor-level:



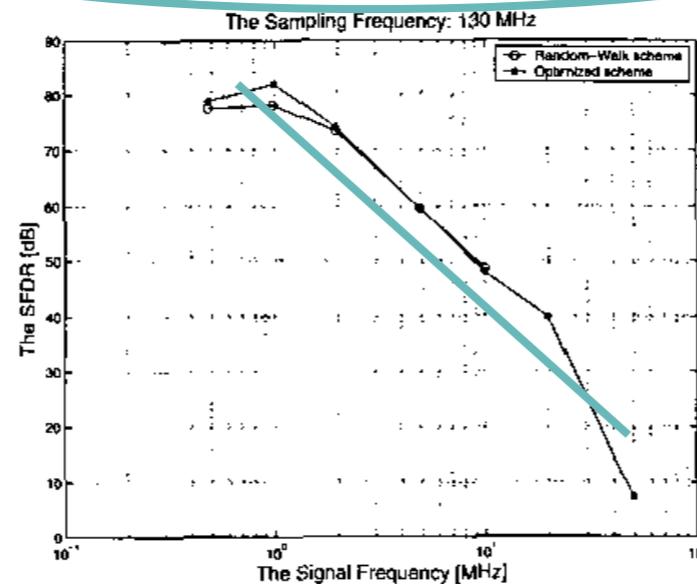
- Why should we care about dynamic properties?
...and not only about INL/ DNL?

SFDR vs. Signal Frequency

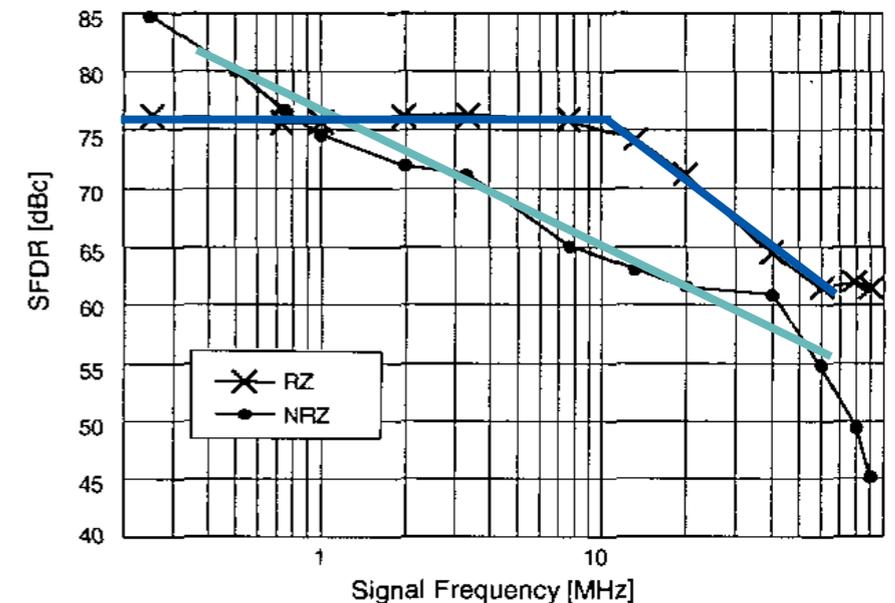
...later!



from:
Bugeja et al., "14-b, 100-MS/s CMOS DAC for spectral performance",
JSSC 1999

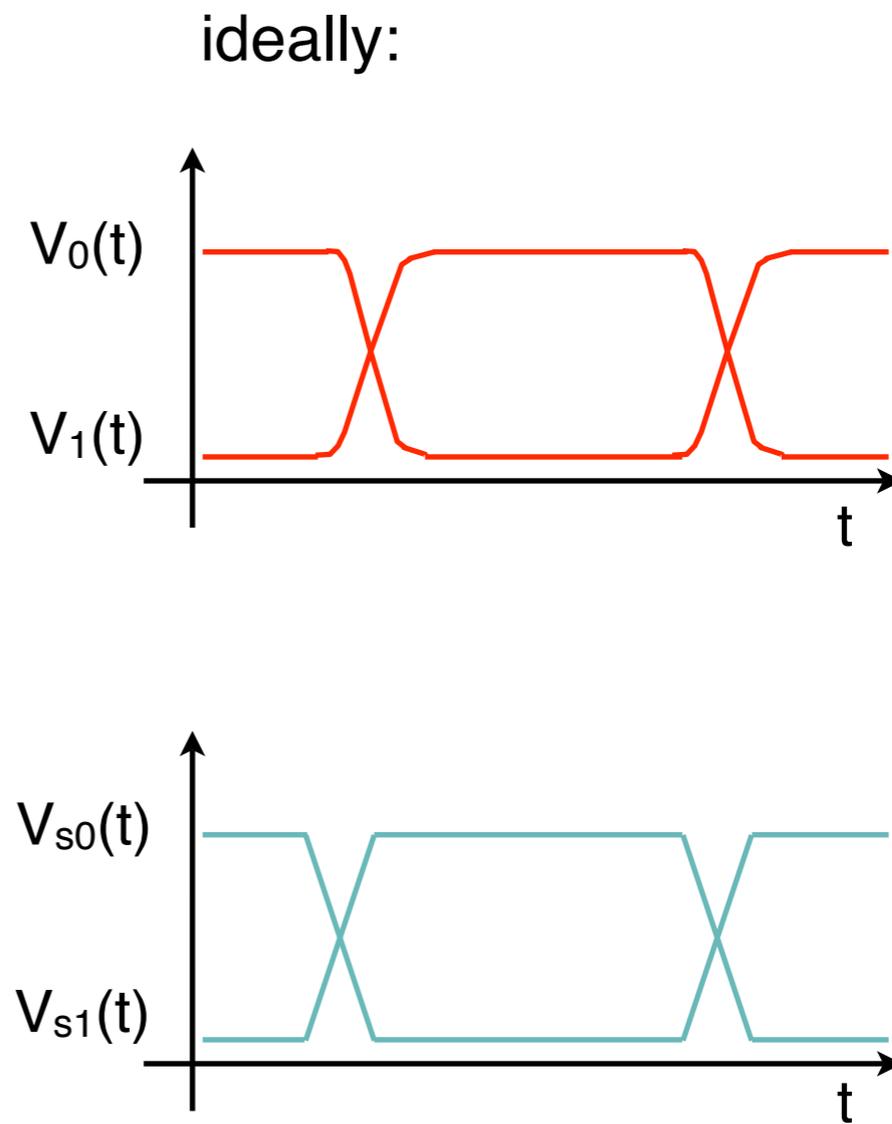
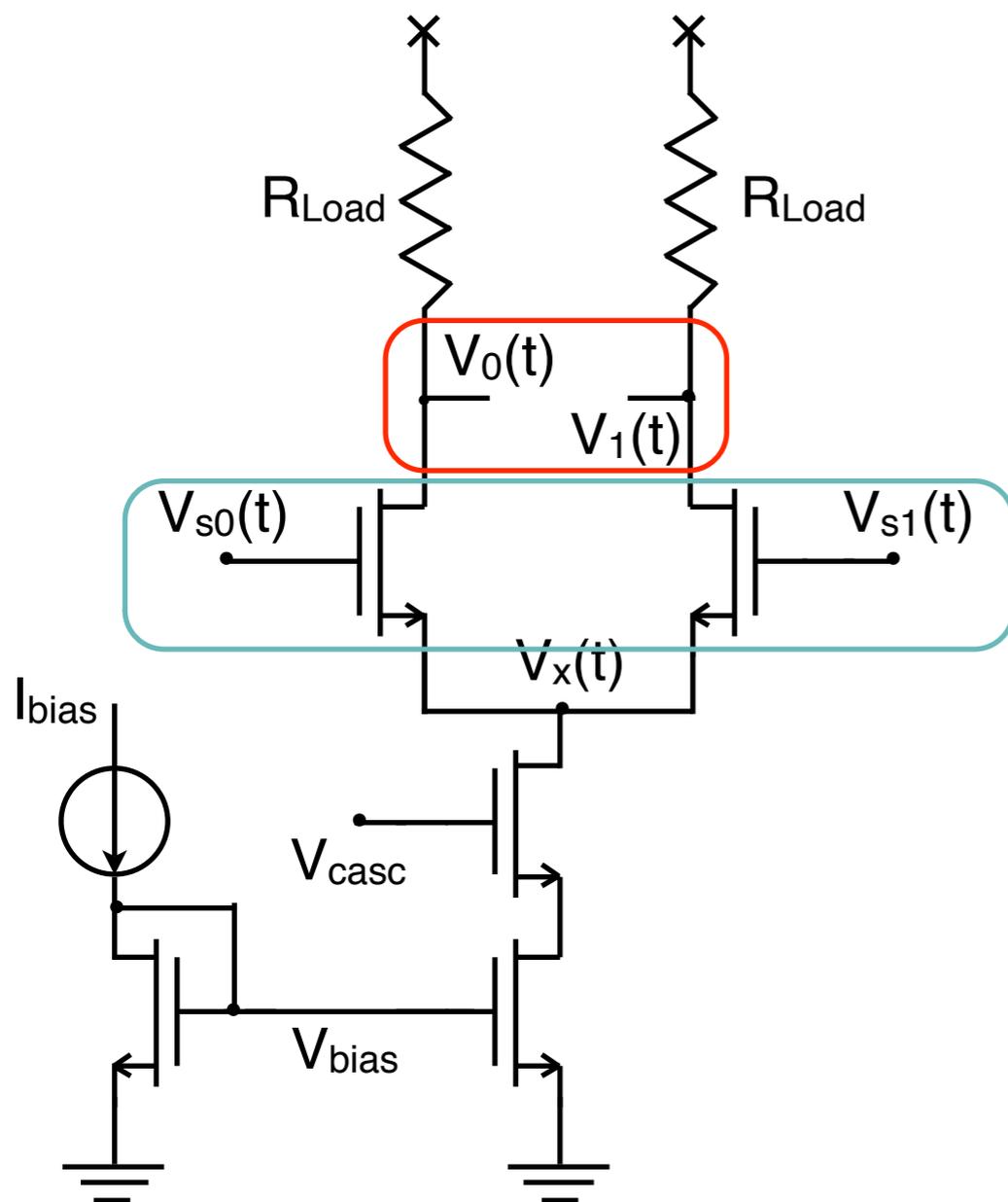


from:
T. Chen, et al., "A 14-bit 130-MHz CMOS Current-Steering DAC with adjustable INL",
ESSCC 2004

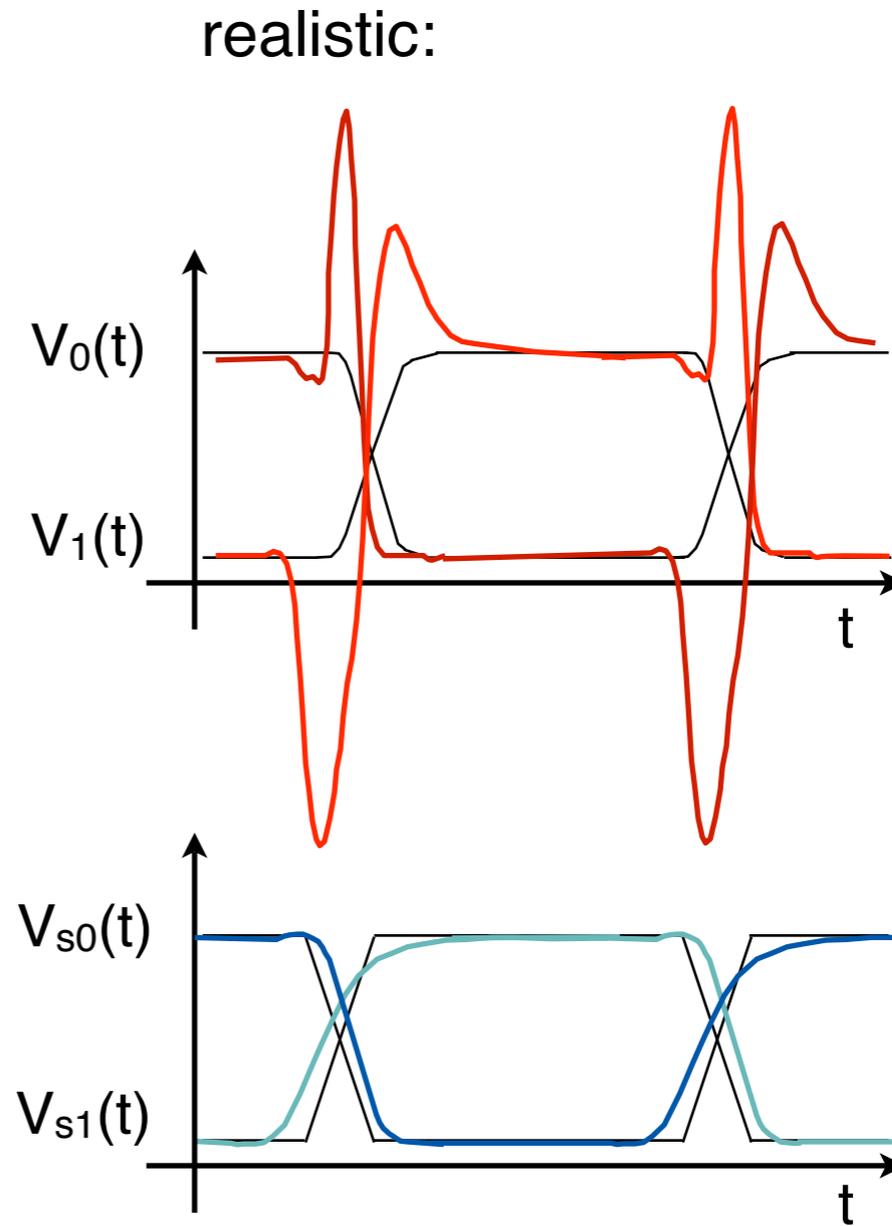
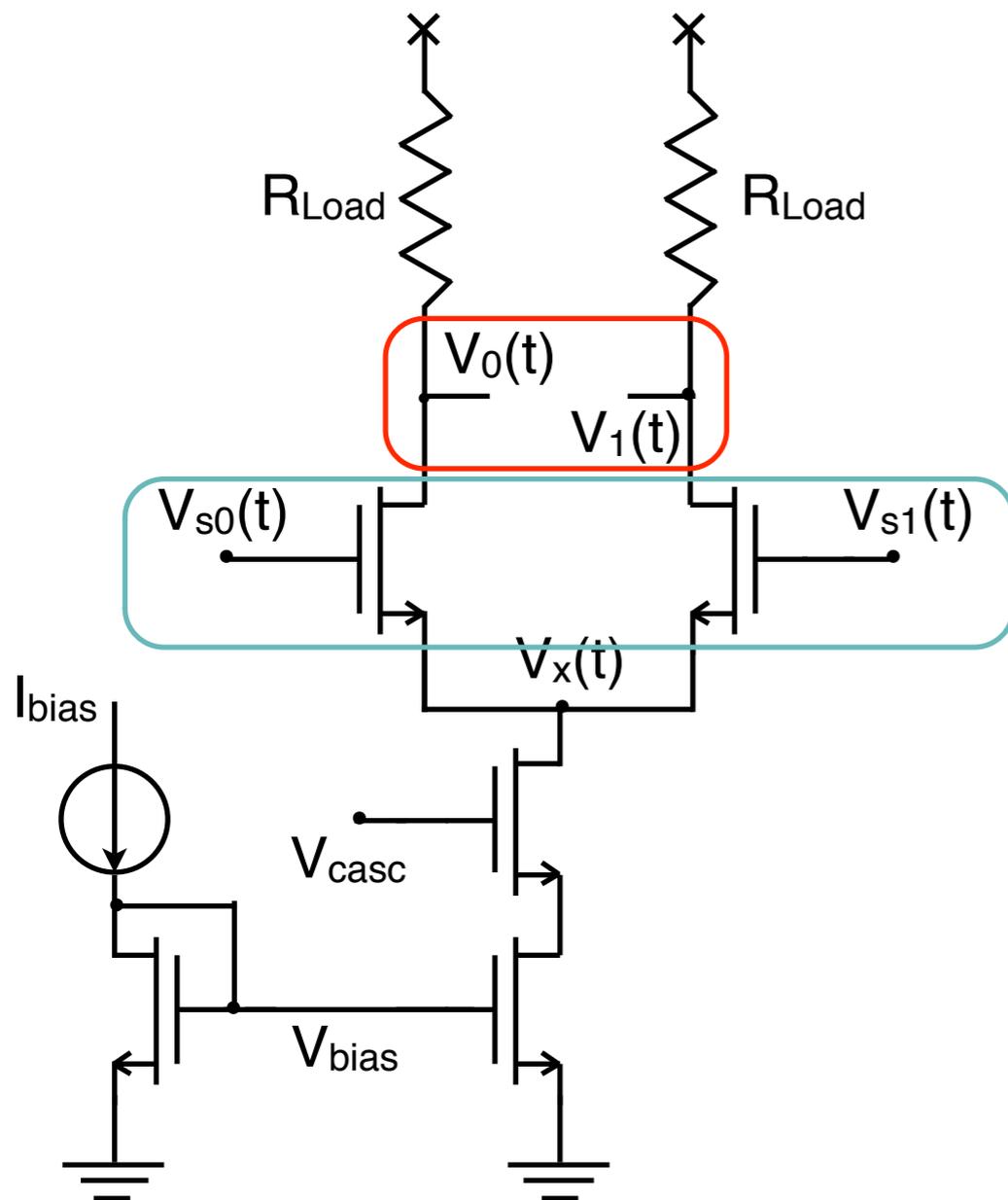


from:
Q. Huang, "Low Voltage and Low Power Aspects of Data Converter Design",
ESSCC 2004

- Switching in Current Steering DACs:

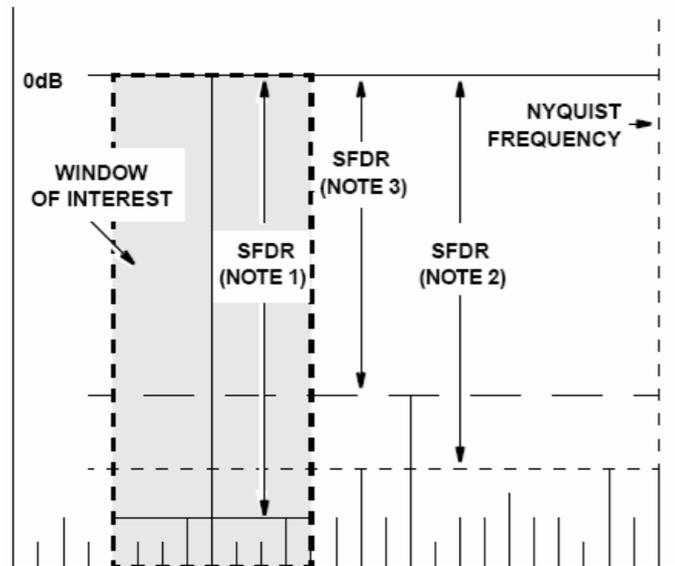


- Switching in Current Steering DACs:



- Switching Delay Differences:
 - Output-Dependent Delay Difference
 - Cell-Dependent Delay Difference
- Errors Introduced while Switching:
 - Switching Crossover
 - Charge Feed-through
- Resampling Circuits
 - Non-Return-to-Zero vs. Return-to-Zero
 - Dual Return-to-Zero Circuit

- SFDR: **S**purious **F**ree **D**ynamic **R**ange



from: E. Balestrieri, et al.,
“Some critical notes on DAC frequency
domain specifications”, IMEKO, 2006.

- many definitions of SFDR exist!
- many definitions of Spur exist, e.g., “non-harmonic”, “any non-signal component”
- various frequency bands of interest
- SFDR is generally a function of input-signal frequency and amplitude, and sampling frequency

- Cell-Dependent Delay Differences:
 - delay differences between current-sources is one of the main differences for bad SFDR.
 - delay determined by position of the current-cell in the layout
 - model discussed:
 - linearly-distributed delays are considered
 - maximum delay difference: d_{\max}

discussed in:
T. Chen and G. Gielen,
*“The analysis and improvement of a current-steering DAC’s dynamic range-I:
The cell-dependent delay differences”*, Jan. 2006.

- Cell-Dependent Delay Differences:
Main results:

- “worst case scenario”:
$$f_0 \leq \frac{2}{\pi d_{\max} 10^{(6.02N+1.76)/20}}$$

e.g.: 10 bits DAC, $d_{\max} = 100$ ps

⇒ max. signal frequency: $f_0 < 5$ MHz

- The distribution of the delay values has the greatest impact on the SFDR, rather than the values itself.

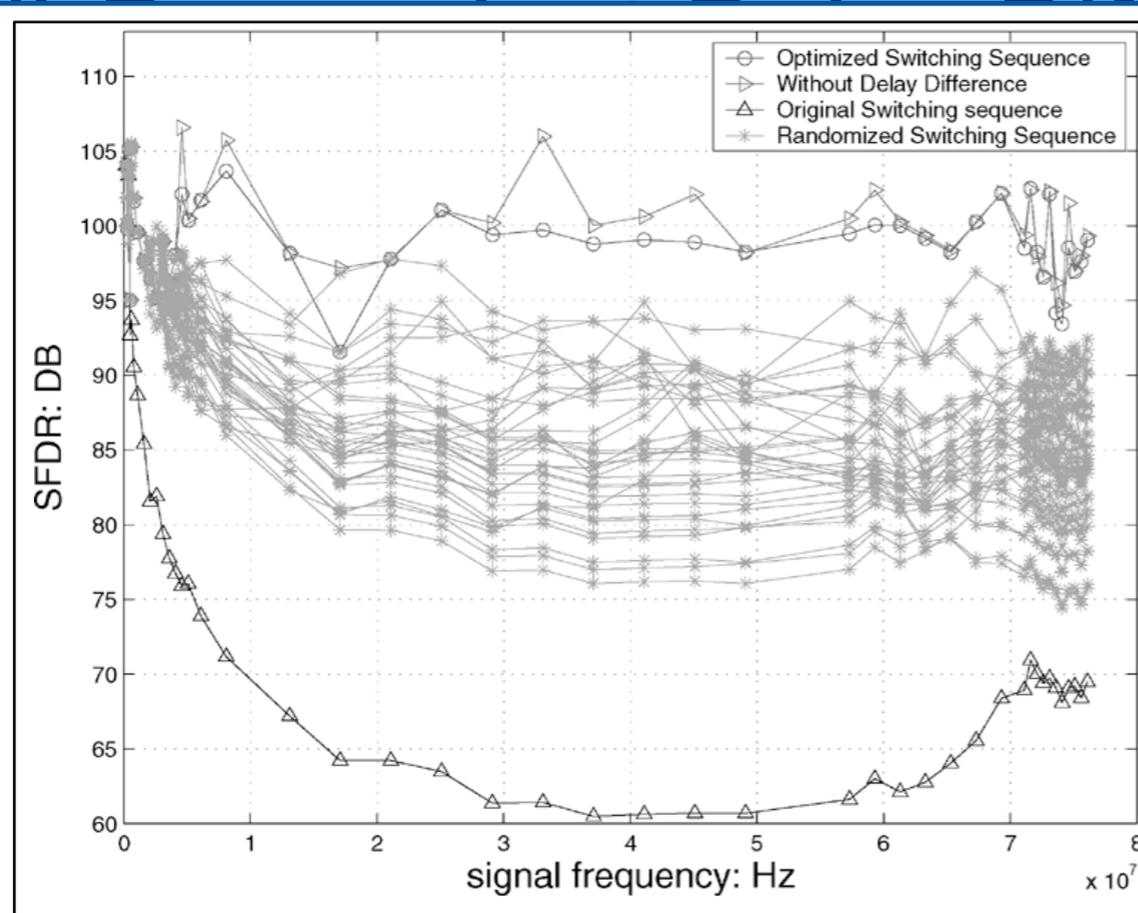
⇒ switching sequence needs to be optimized

discussed in:

T. Chen and G. Gielen,

“The analysis and improvement of a current-steering DAC’s dynamic range-I: The cell-dependent delay differences”, Jan. 2006.

- Cell
- Ma



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from T. Chen and G. Gielen,
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- Output-Dependent Delay Differences:

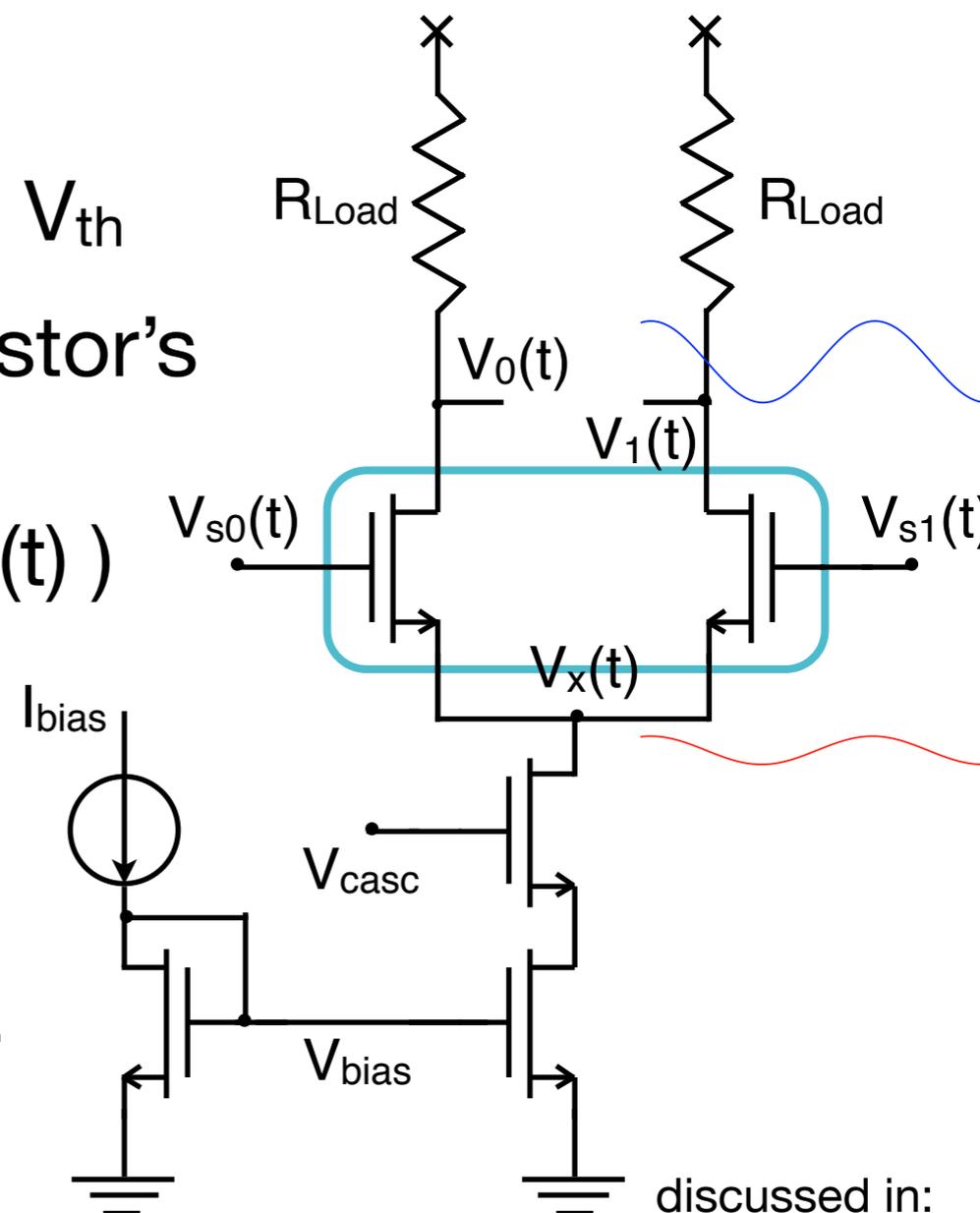
- Origin:

- A transistor switches at $V_{gs} = V_{th}$
- Because of the Switch-transistor's limited $(g_m \cdot r_o)$:

$$V_x(t) = f(V_0(t), V_1(t), V_{s0}(t), V_{s1}(t))$$

- $V_x(t) \approx V_0 / (1 + g_m r_o)$

g_m, r_o : transconductance and output resistance of the switch transistor



discussed in:

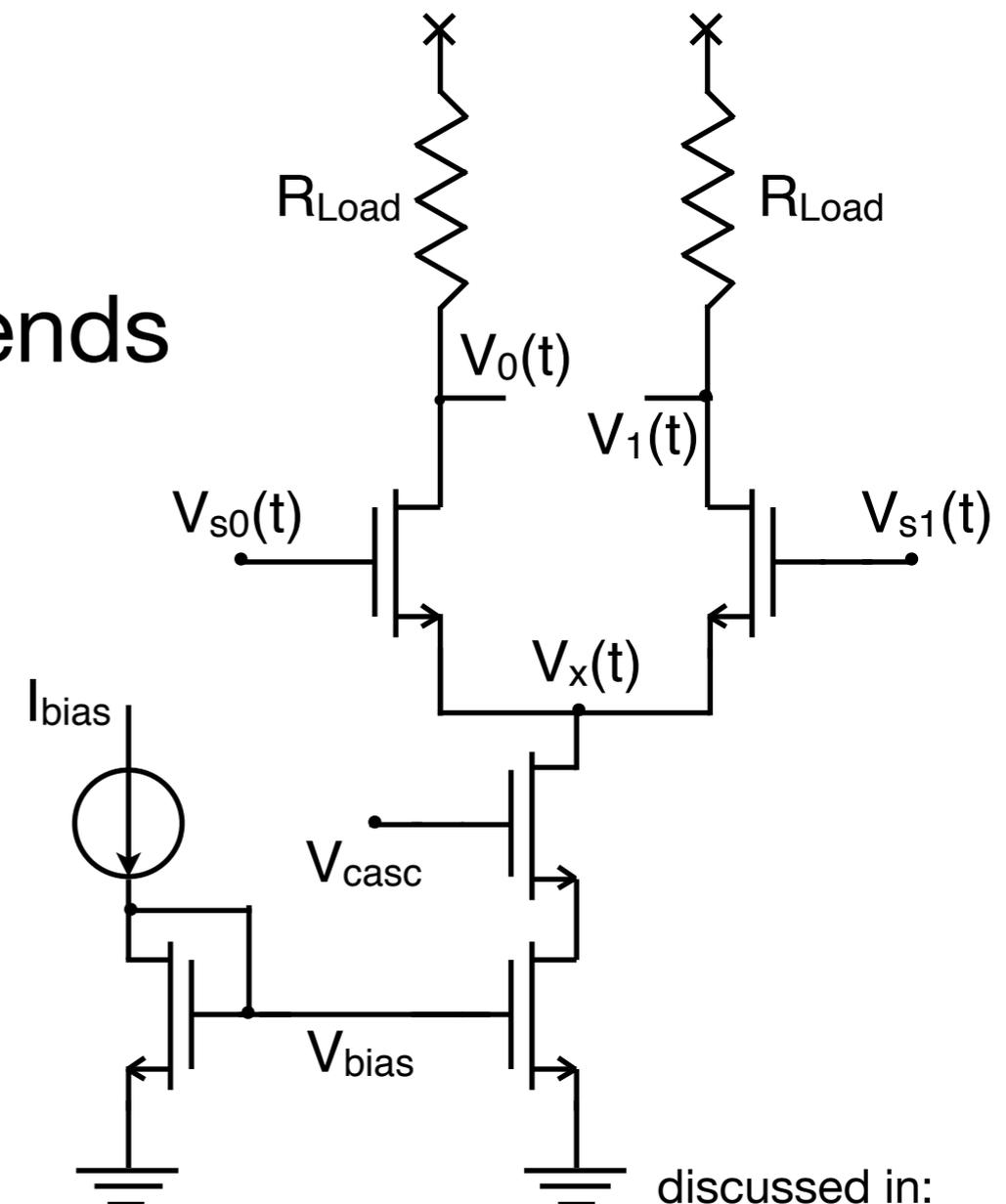
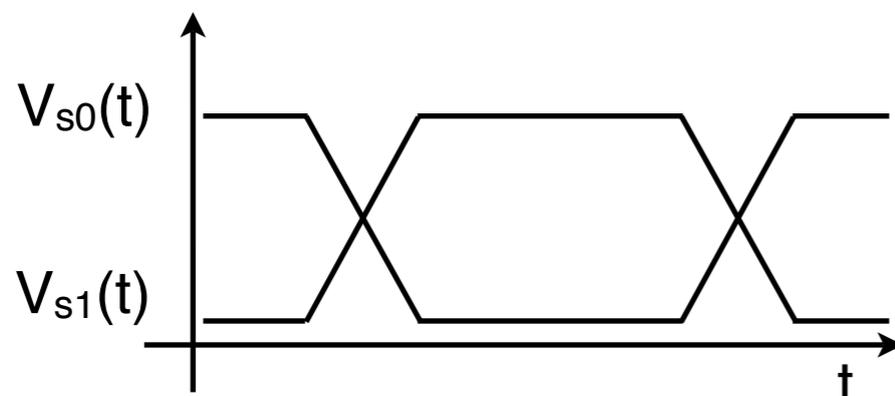
T. Chen and G. Gielen,

“The analysis and improvement of a current-steering DAC’s dynamic range-II: The output-dependent delay differences”, Feb. 2007.

- Output-Dependent Delay Differences:

- As the clock-signals $V_{si}(t)$ have a finite slope and
- the source voltage $V_x(t)$ depends on the output voltage, $V_i(t)$,

⇒ the switch-delay depends on the output voltage.



discussed in:

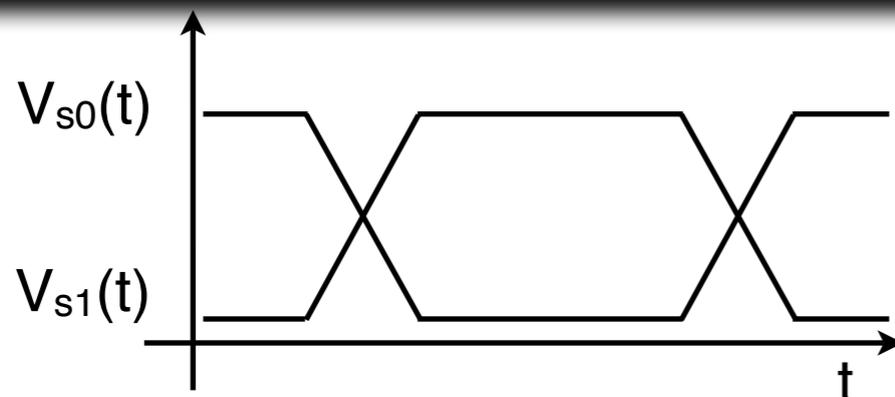
T. Chen and G. Gielen,

“The analysis and improvement of a current-steering DAC’s dynamic range-II: The output-dependent delay differences”, Feb. 2007.

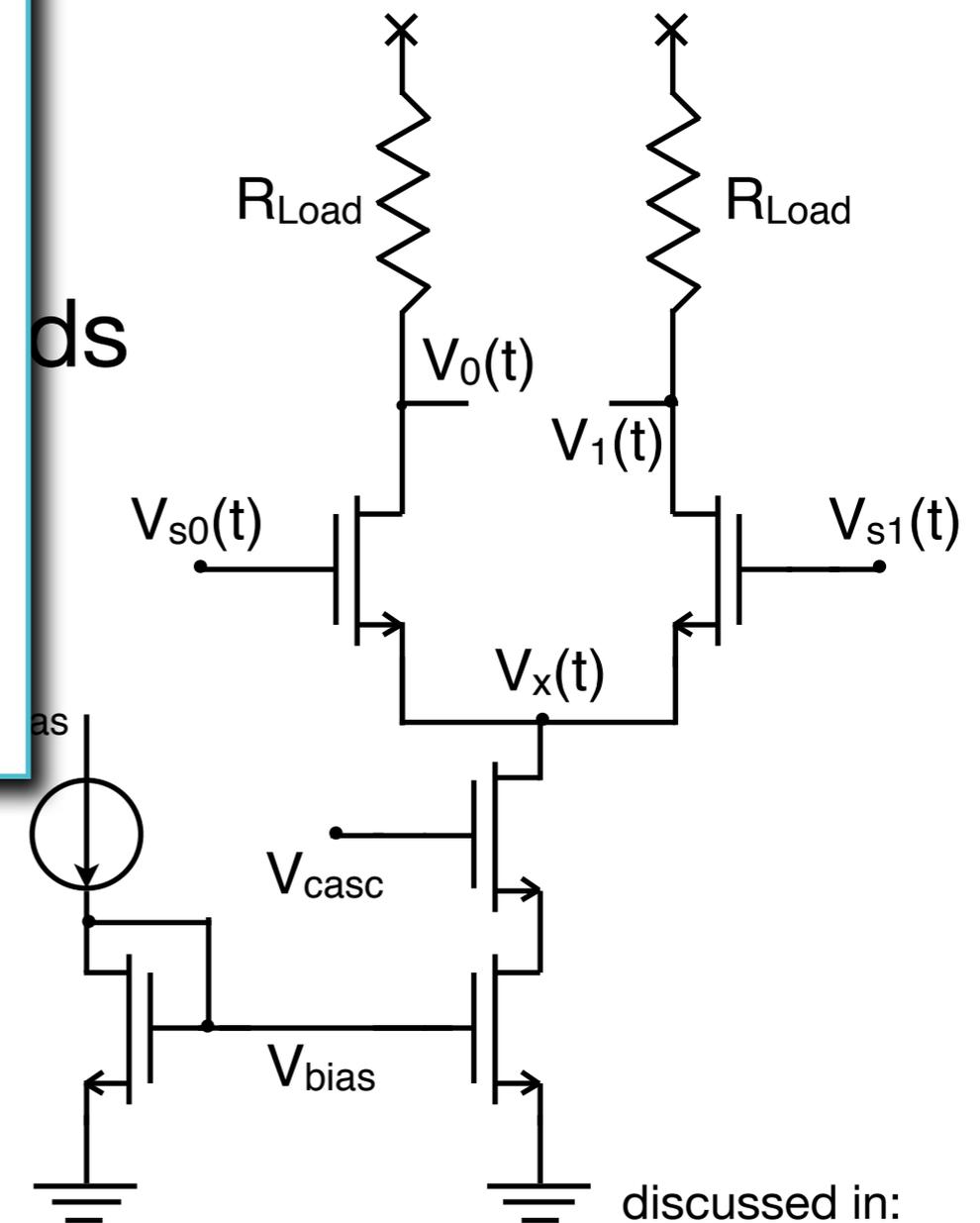
Practical Example:

- max. output voltage swing: 0.5 V
- $g_m r_o \approx 10$
- max. source voltage (V_x) variation: ≈ 0.05 V
- rising speed of clock: 1.25 V/ns

⇒ resulting delay difference: 40 ps



Differences:



discussed in:
T. Chen and G. Gielen,

“The analysis and improvement of a current-steering DAC’s dynamic range-II: The output-dependent delay differences”, Feb. 2007.

- Output-Dependent Delay Differences:
 - Effects on the SFDR:

single-ended output:

$$\text{SFDR} = \frac{4}{\omega_0 d_{\max}} \sqrt{\frac{1 + 4\omega_0^2 \tau^2}{1 + \omega_0^2 \tau^2}}$$
$$\text{SFDR} \approx \frac{4}{\omega_0 d_{\max}}$$

SFDR decreases with:

increasing d_{\max}

increasing signal frequency ω_0

differential output:

$$\text{SFDR} = \frac{32\tau}{\omega_0 d_{\max}^2} \sqrt{\frac{1 + 9\omega_0^2 \tau^2}{1 + \omega_0^2 \tau^2}}$$
$$\text{SFDR} \approx \frac{32\tau}{\omega_0 d_{\max}^2}$$

SFDR decreases with:

increasing d_{\max}

increasing signal frequency ω_0

decreasing time constant τ

discussed in:

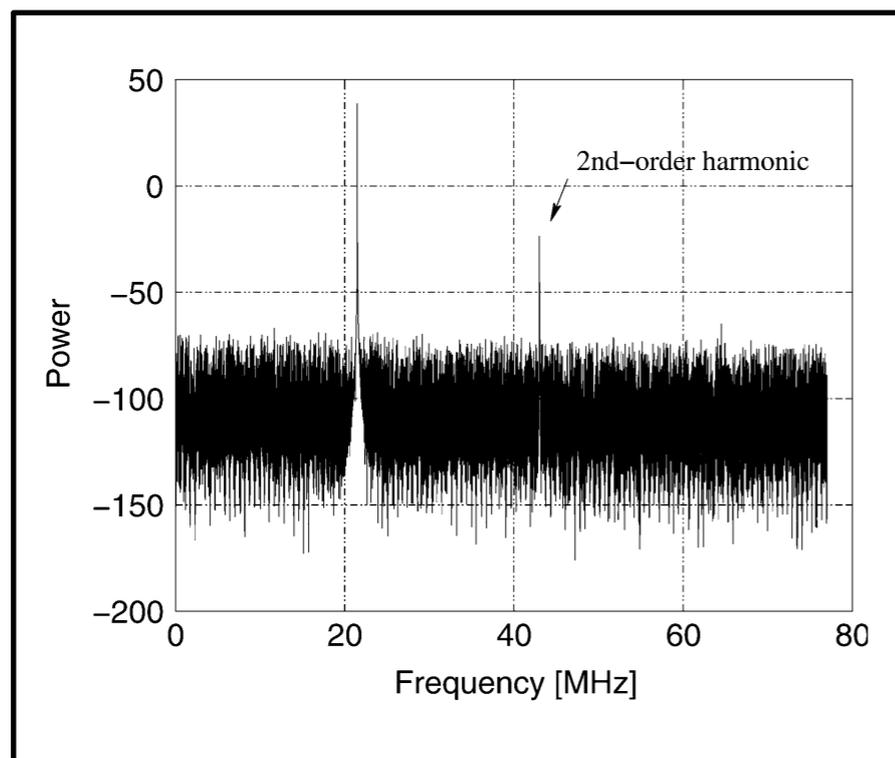
T. Chen and G. Gielen,

“The analysis and improvement of a current-steering DAC’s dynamic range-II:

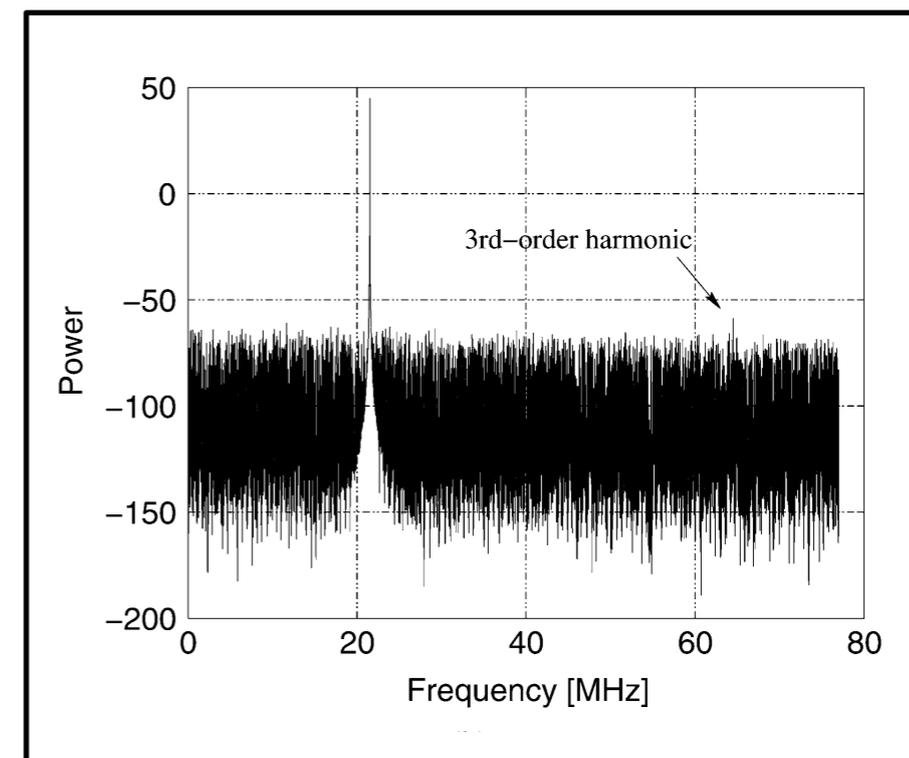
The output-dependent delay differences”, Feb. 2007.

- Output-Dependent Delay Differences:
 - Effects on the SFDR:

single-ended output:



differential output:



discussed in:
T. Chen and G. Gielen,
*"The analysis and improvement of a current-steering DAC's dynamic range-II:
The output-dependent delay differences"*, Feb. 2007.

- Output-Dependent Delay Differences:
 - Measures against it:
 - increase ($g_m \cdot r_0$) of switches
 - add a cascode stage for switch (if voltage headroom permits)
 - scale the switches to increase $g_m \cdot r_0$
 - accelerate switching speed
 - add an RZ stage

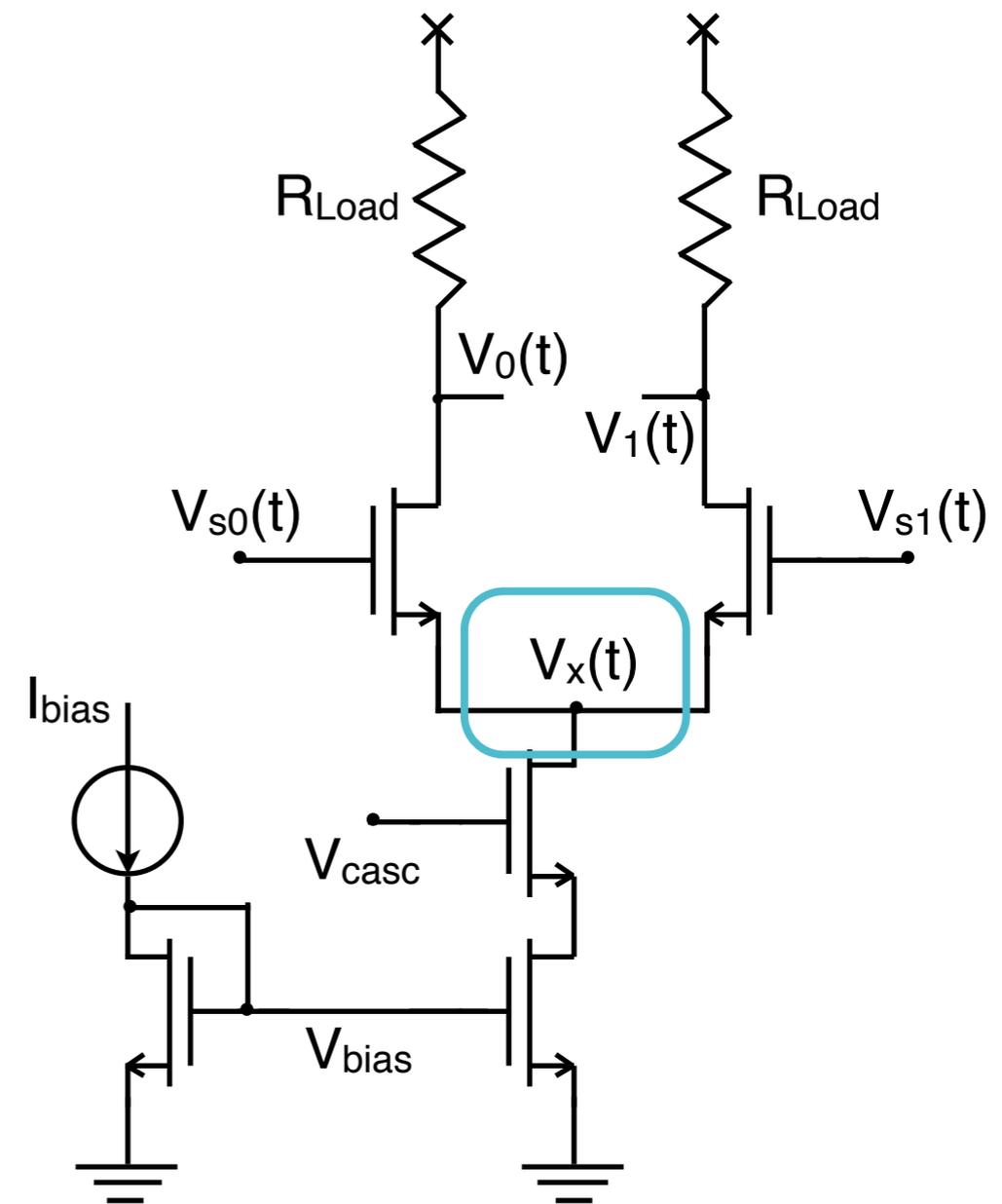
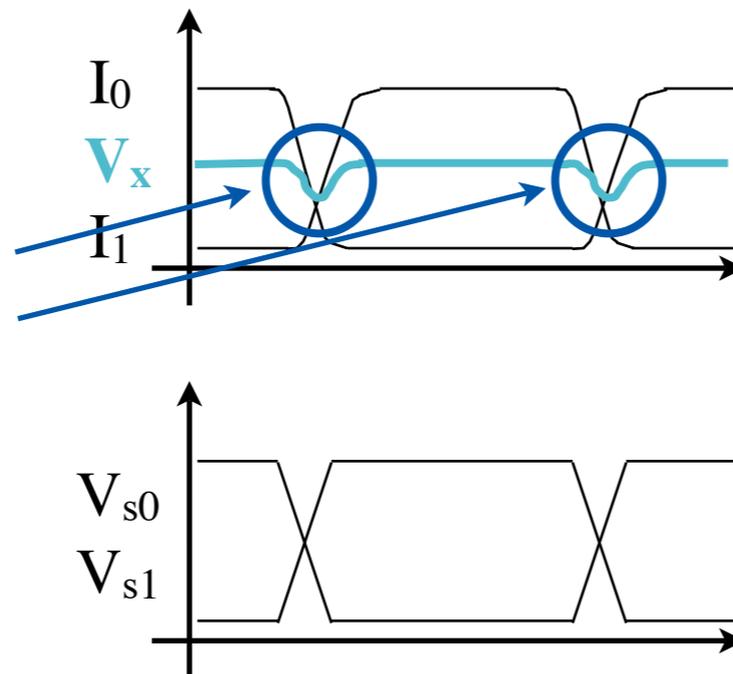
discussed in:
T. Chen and G. Gielen,
*“The analysis and improvement of a current-steering DAC’s dynamic range-II:
The output-dependent delay differences”*, Feb. 2007.

- Errors introduced while Switching:
 - “turning on”-transistor reaches different regions of operation at different times than its complementary “turning off” transistor.

short time where both differential current-switches are off

→ abrupt discharge with steep transient

→ voltage V_x drops



- Charge feed-through:
 - common problem for all SC- and SI-circuits
 - first order proportional to
 - switch-capacitance (switch-size)
 - switch-driving signal slope
 - switch-driving signal swing
 - ideal switching scheme (for min. feed-through):
 - small switch
 - slow switch-driving signal
 - small switch-driving signal swing

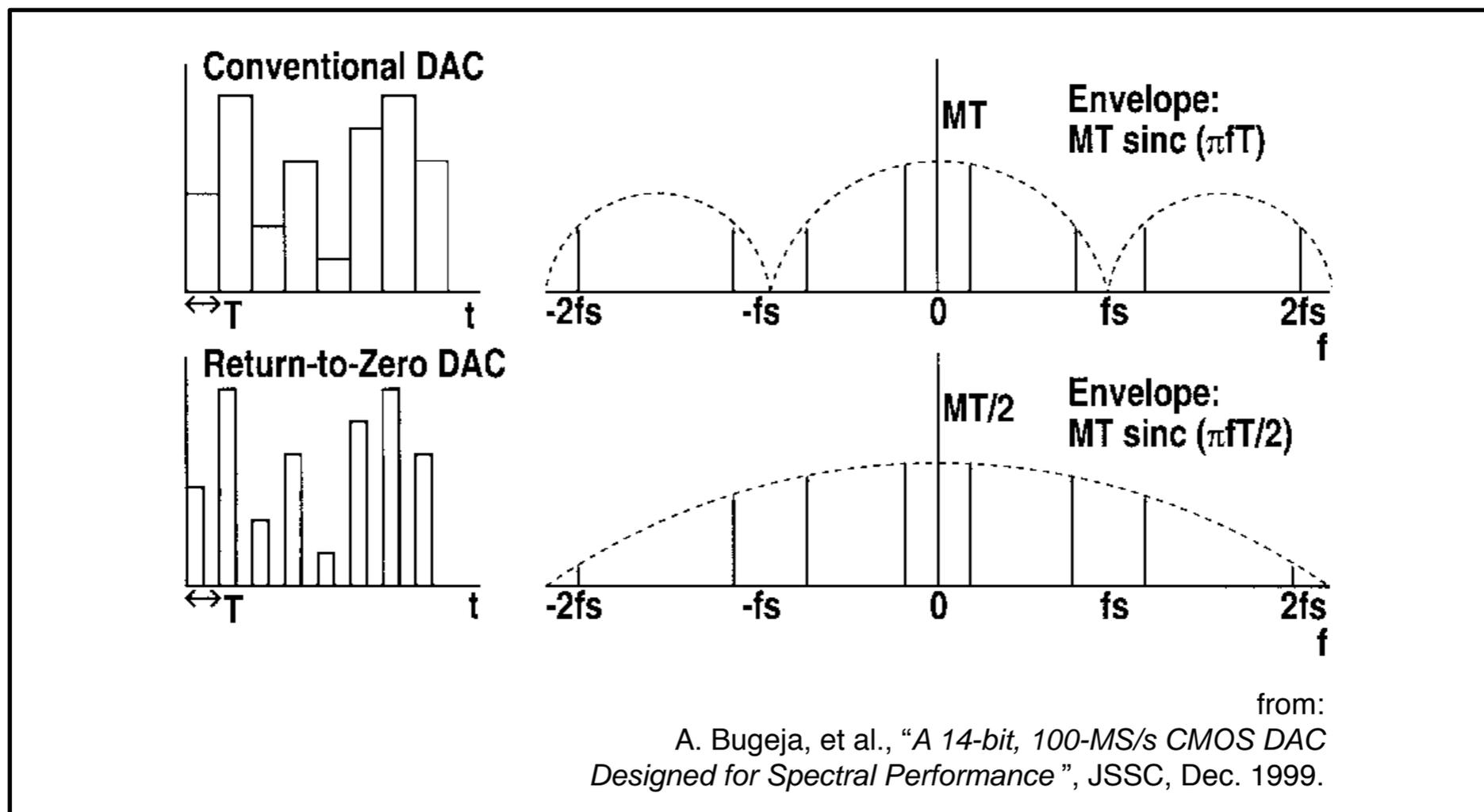
- How to improve switching behavior
 - ideal switching scheme:
 - for min. feed-through:
 - small switch
 - slow switch-driving signal
 - small switch-driving signal swing
 - for small output-dep. delay differences:
 - increase size of switches for large ($g_m \cdot r_0$)
 - for short crossover time:
 - fast switching to minimize switching time

- How to improve switching behavior
 - ideal switching scheme:
 - for min. feed-through

Switch Optimization:

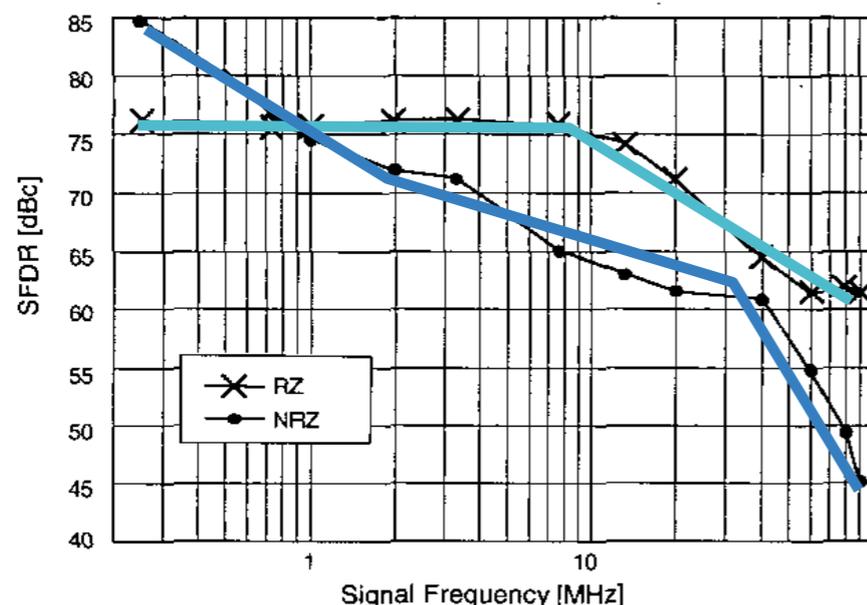
- find ideal trade-off for switch-size (use cascode if head-room permits)
 - slow switching signal, but with small signal-swing
- f crossover time:
- fast switching to minimize switching time

- NRZ vs. RZ, dual RZ:
 - RZ, return-to-zero circuit:
 - each pulse returns to zero for a portion of the clock period



- NRZ vs. RZ, dual RZ:
 - RZ, return-to-zero circuit:
 - each pulse returns to zero for a portion of the clock period
 - solves inter-symbol interference problem
 - halves the output signal power, extra circuitry power
 - reduces SFDR for low frequency input signals

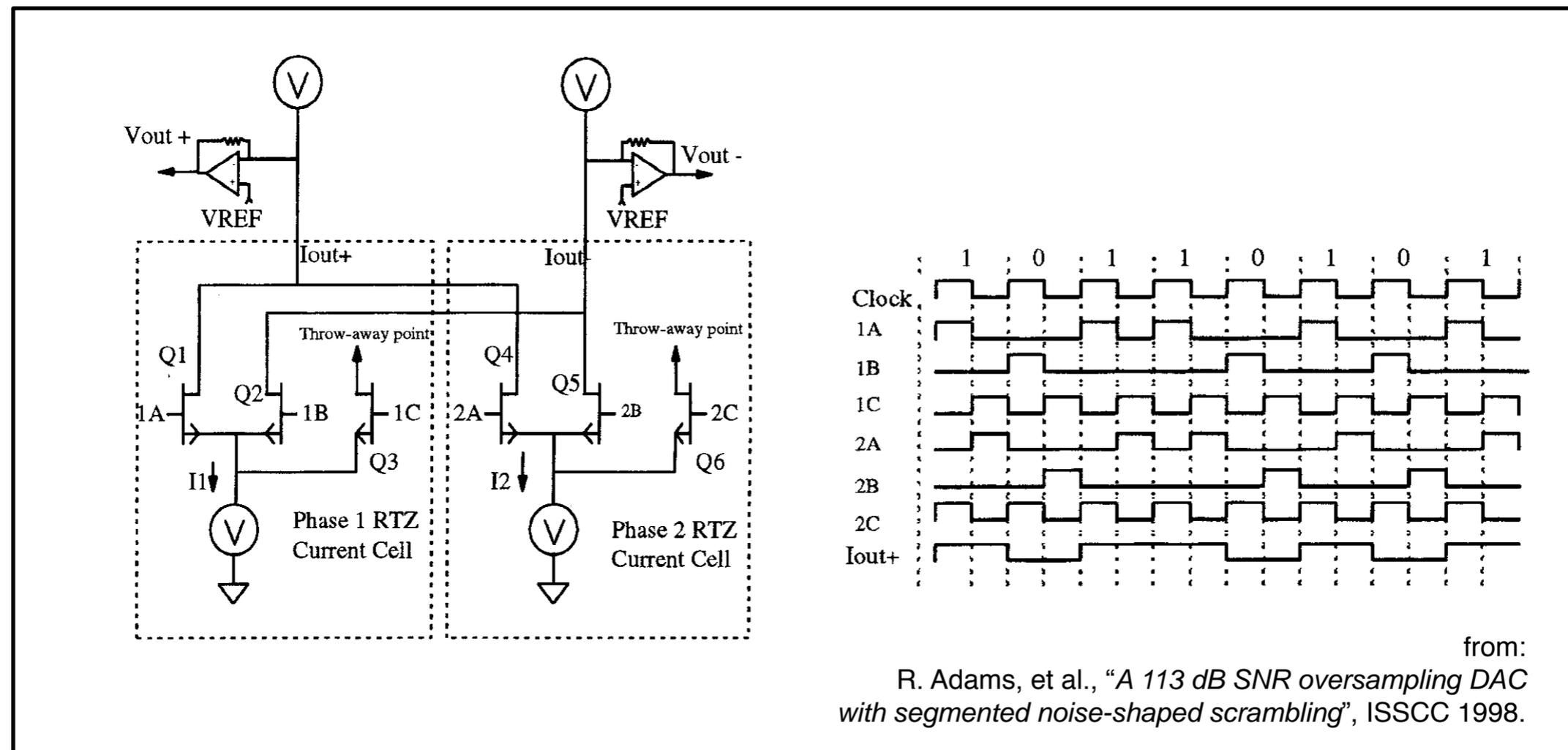
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from:

Q. Huang, "Low Voltage and Low Power Aspects of Data Converter Design", ESSCC 2004

- Dual RZ:
 - RZ, return-to-zero circuit:
 - combines two shifted RZ-pulses to a single pulse

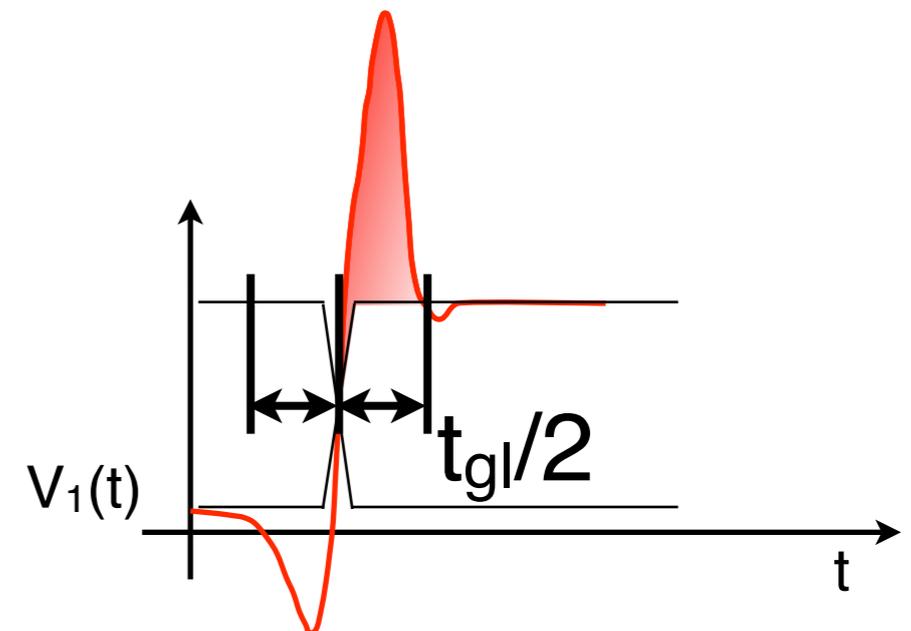


- Dual RZ:
 - RZ, return-to-zero circuit:
 - combines two shifted RZ-pulses to a single pulse
 - solves inter-symbol interference problem
 - large circuit overhead

- Simple Mathematical Model of a Current-Steering DAC's Output
 - Code-Transition
 - Output-Dependent Delay Difference
 - The Simulink Model
- Future Work
 - Check whether the Model is precise enough
 - Build a Feedback Loop to Correct Non-Idealities

- Glitch “Energy”, E_{gl} :
 - sometimes called “Glitch Area”
 - not an energy, but voltage integrated over time
 - Unit: often [pV · s]
 - many different definitions

“my” definition:



- Glitch Time, t_{gl} :
 - “time during which the glitch occurs”

- Current-Source Switching:
 - Code-Transition modeled by
 - shifted “tanh”-function
 - +
 - exponentially-damped sinusoid as glitch

$$i_{\text{out}} = A_{\text{gl}} \sin\left(\frac{2\pi}{t_{\text{gl}}}(t - t_0)\right) \exp\left(-\text{sign}(t - t_0) \frac{2\pi}{t_{\text{gl}}}(t - t_0)\right) + \frac{\text{level}_{i+1} - \text{level}_i}{2} \tanh\left(\frac{2\pi}{t_{\text{gl}}}(t - t_0)\right) + \frac{\text{level}_{i+1} + \text{level}_i}{2}$$

discussed in:
J. Vandebussche et al.,
“Systematic Design of High-Accuracy Current-Steering
D/A Converter Macrocells for Integrated VLSI Systems”, TCAS-II, March 2001.

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$$\frac{E_{\text{gl}}}{2R_{\text{load}}} n_{\text{switched}} = \left[A_{\text{gl}} \sin\left(\frac{2\pi}{5}\right) \exp\left(-\frac{2\pi}{5}\right) + \frac{1}{2} \frac{\text{level}_{i+1} - \text{level}_i}{2} \left(\tanh\left(\frac{2\pi}{5}\right) - 1 \right) \right] \frac{t_{\text{gl}}}{4}$$

– Parameters:

- Glitch Energy, $E_{\text{gl}} \rightarrow$ Glitch Amplitude A_{gl}
- Glitch Time, t_{gl}
- number of switches
(involved in the code-transition)

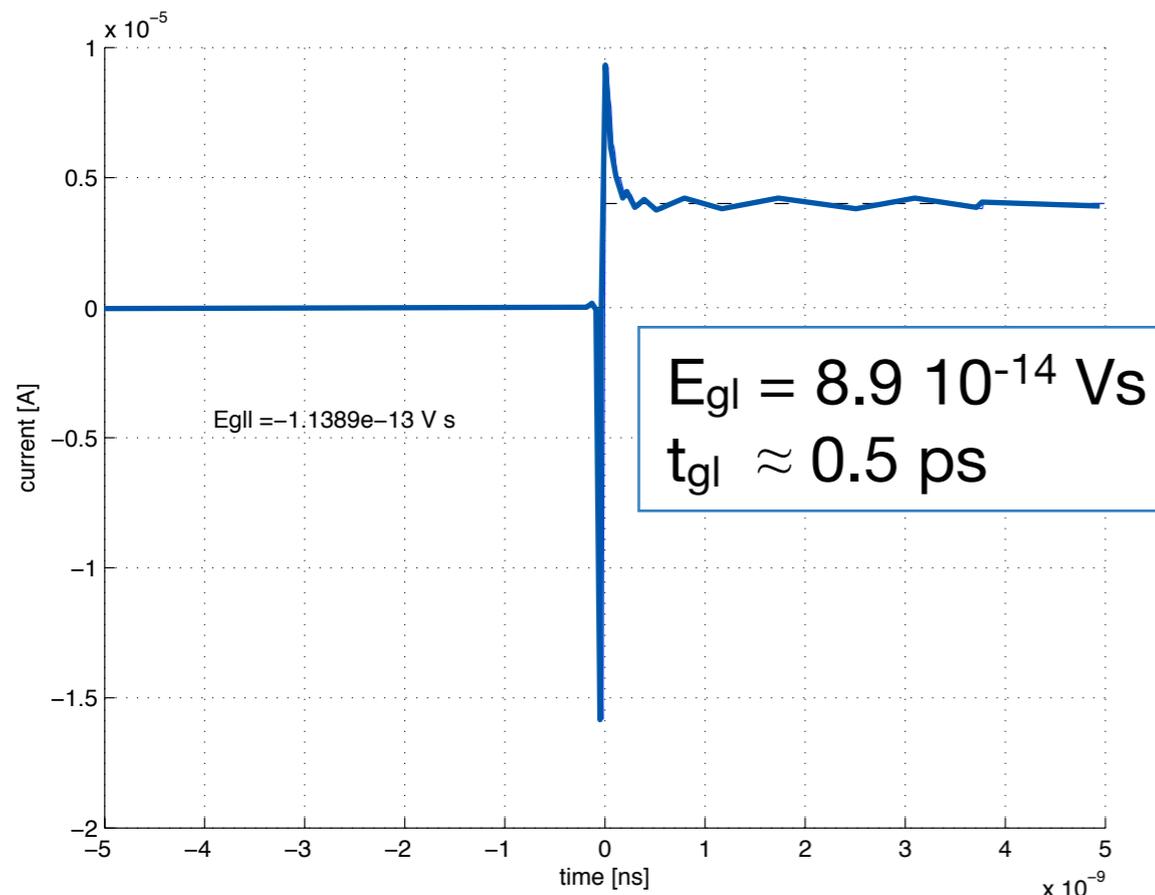
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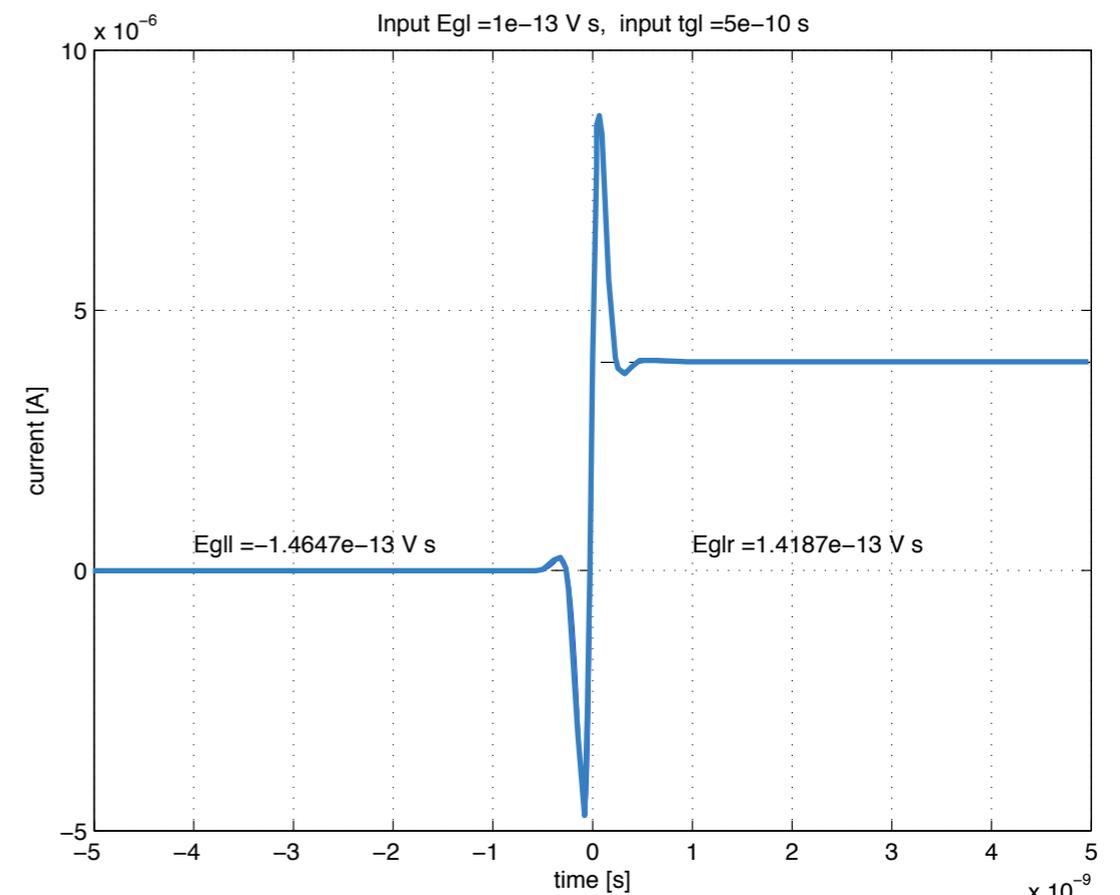
“Systematic Design of High-Accuracy Current-Steering D/A Converter Macrocells for Integrated VLSI Systems”, TCAS-II, March 2001.

- From Transistor-Level to High-Level

1) Transistor-Level Simulation in Cadence:

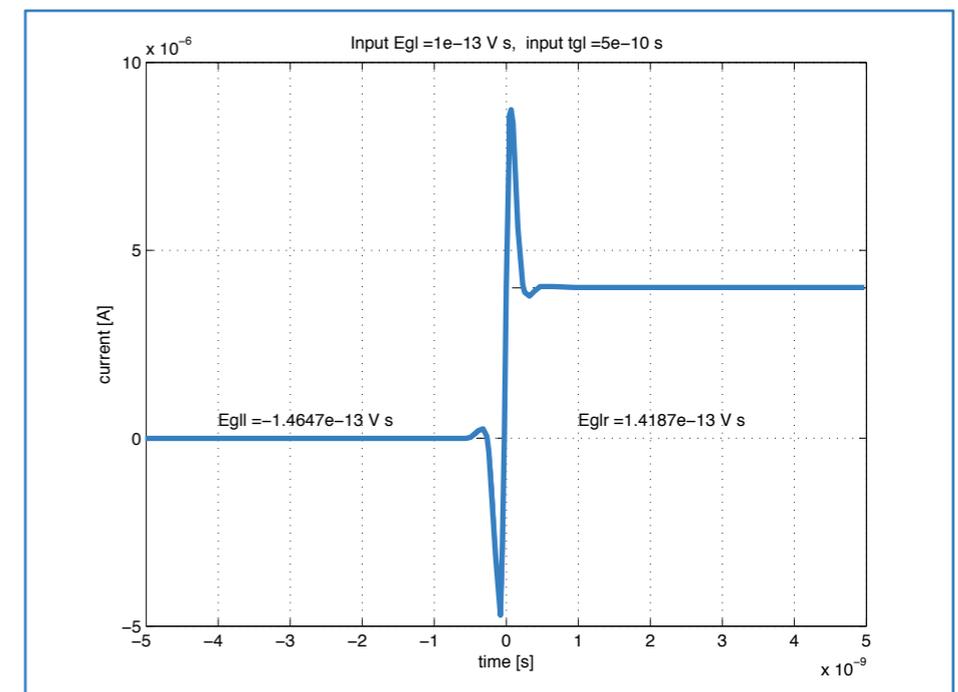
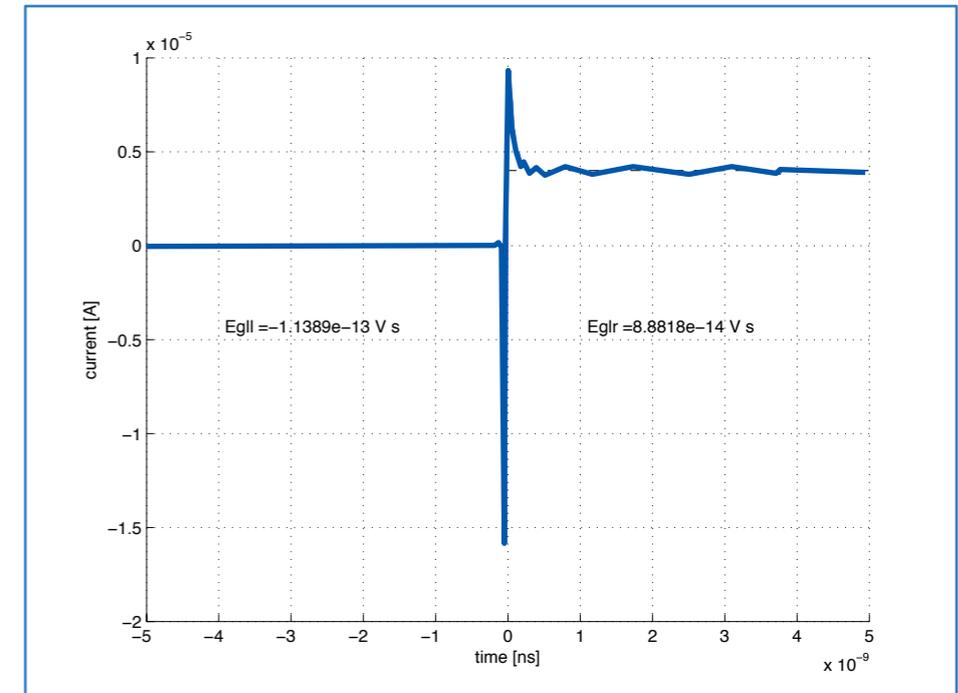


3) High-Level Simulation with Extracted Parameters:

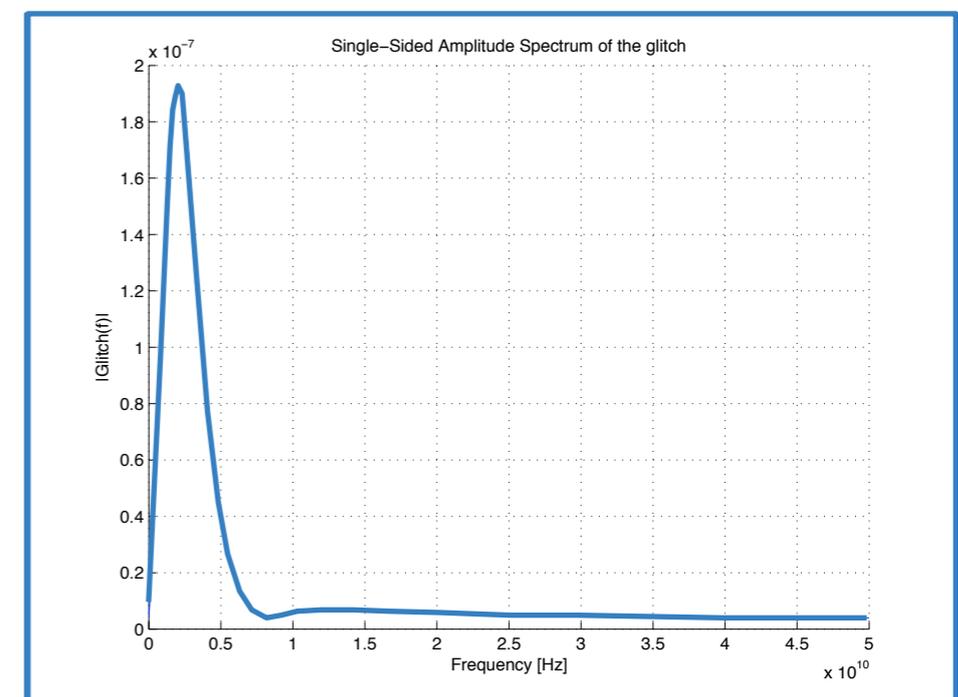
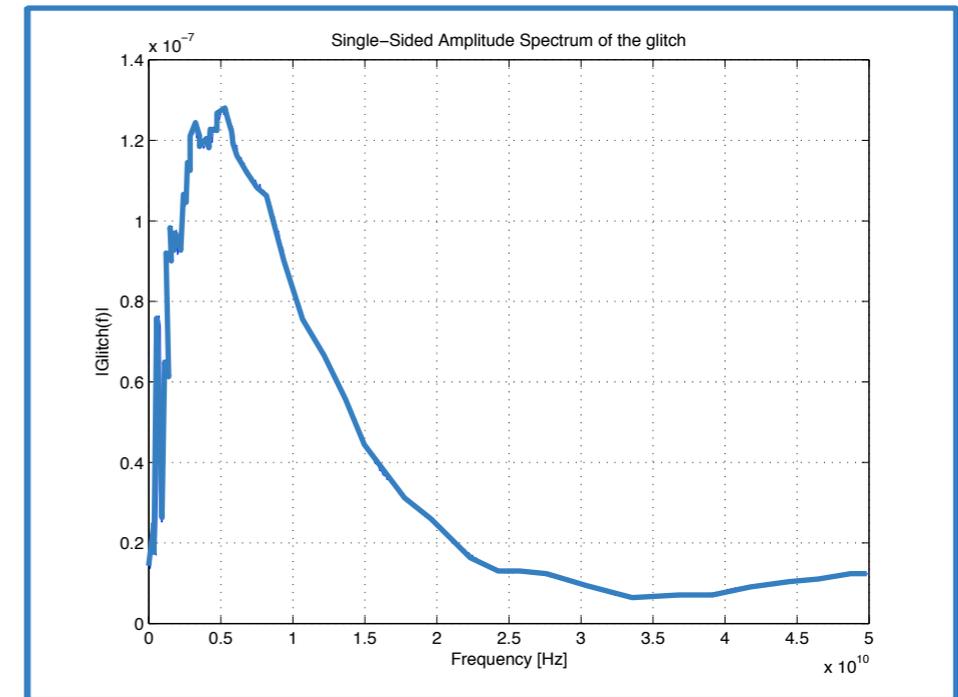


2) Extract Parameters E_{gl} , t_{gl}

- From Transistor-Level to High-Level
- Is the model precise enough?
 - Glitches are more symmetric in the mathematical model than in Cadence
 - With the same glitch-time, t_{gl} , the high-level simulation has a smaller bandwidth.



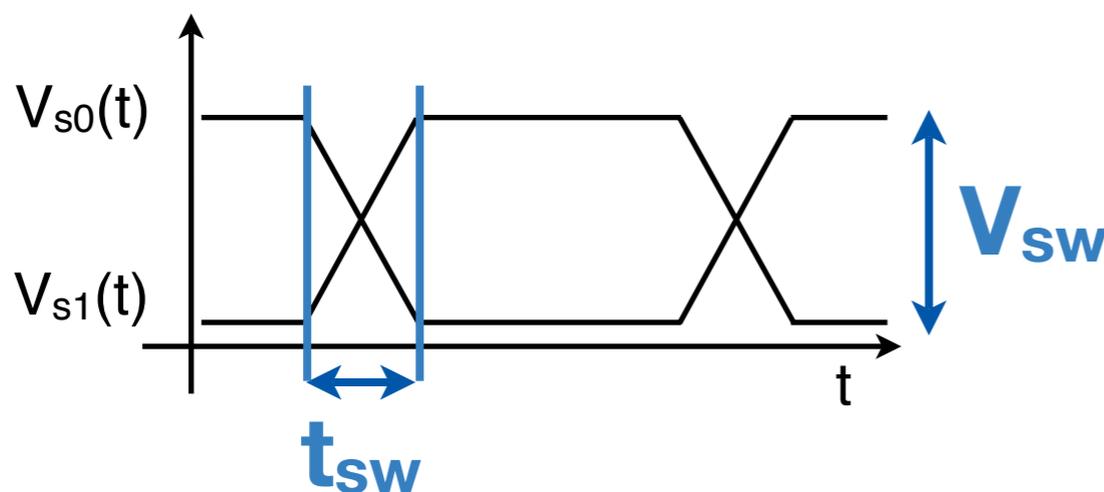
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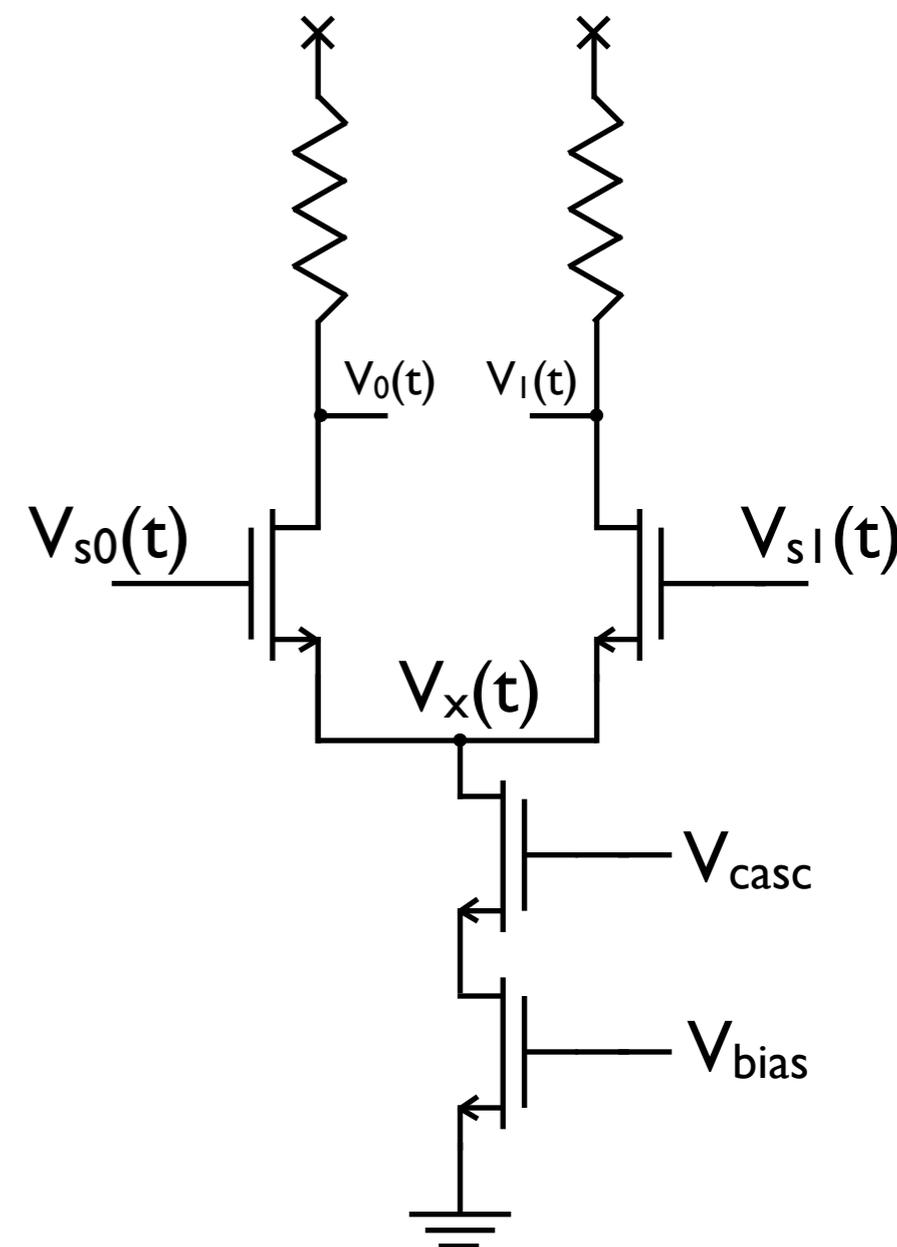
- Output-Dependent Delay Difference

$$V_X(t) = \frac{V_0(t)}{1 + g_m r_0}$$

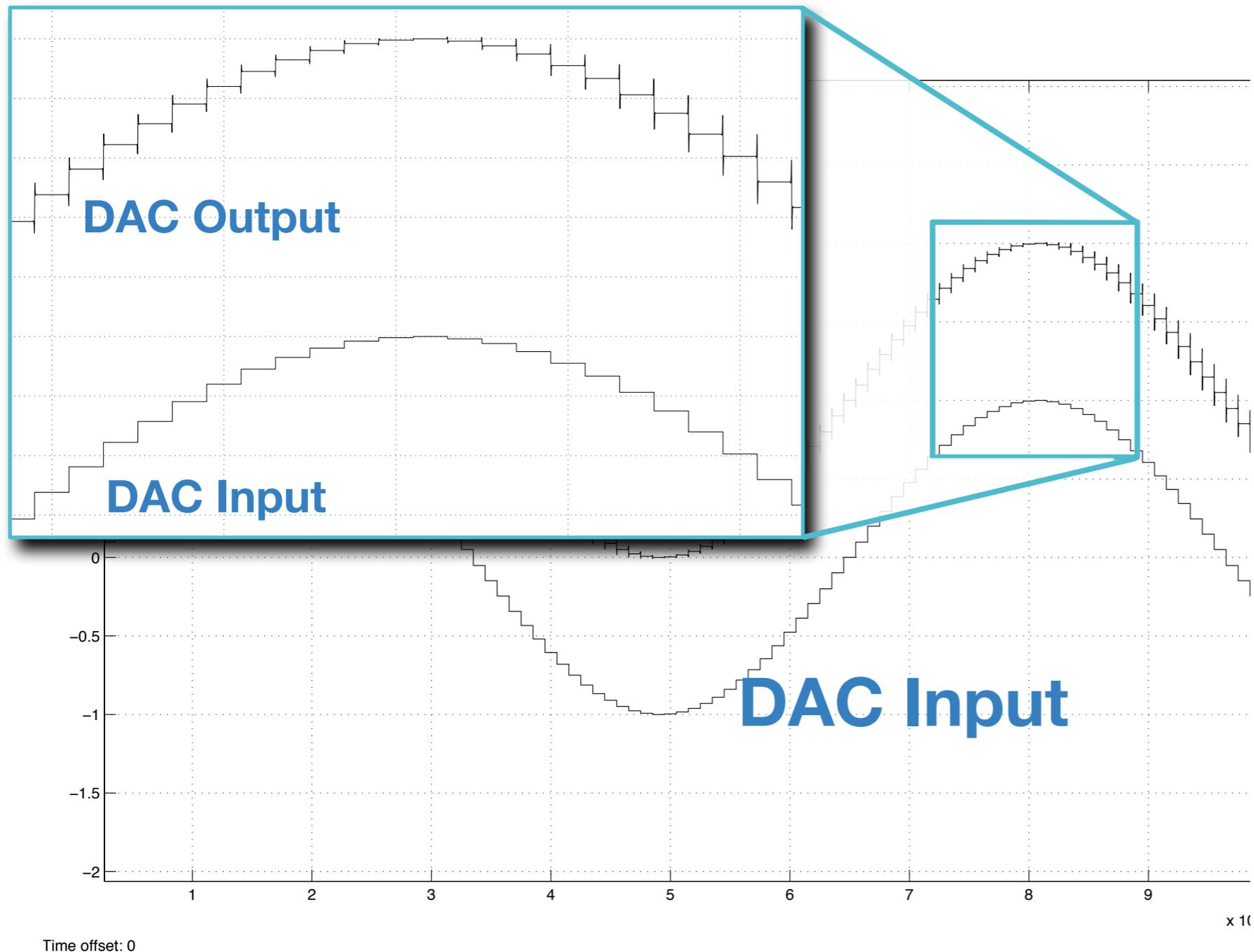
$$t_{\text{delay}} = \frac{t_{sw}}{V_{sw}(V_{th} + V_X(t))}$$



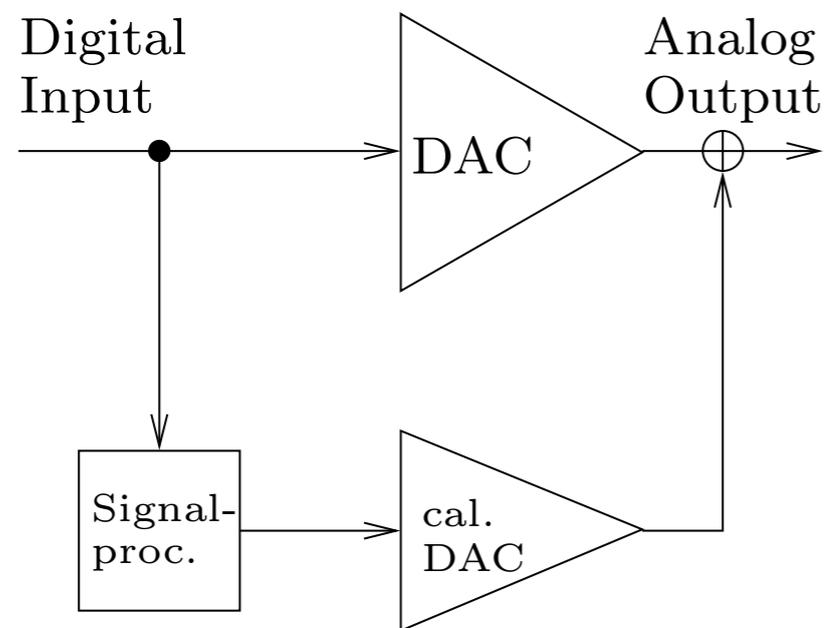
$$t_{\text{delay}} = \frac{t_{sw}}{V_{sw}\left(V_{th} + \frac{V_0(t)}{1 + g_m r_0}\right)}$$



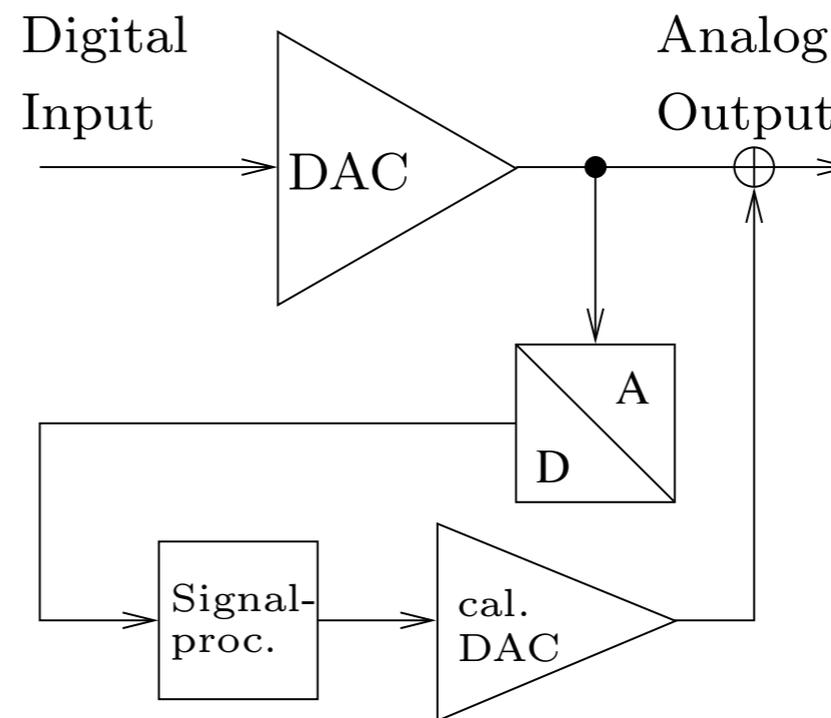
- Output of the Simulink Model:



- Check if Model's Precision is enough
- Design Feedback Loop to Correct Non-Idealities of DAC-Settling



(a) Feedforward with a separate calibration DAC.



(b) Feedback with a separate calibration DAC.

- The settling behavior of a current-steering DAC was discussed.
- Various reasons for SFDR degradation in current-steering DACs was presented.
- Hints for the design of the switches in current-steering DACs were given.
- A simple mathematical model of a current-steering DAC was presented.

Thank you for your interest!

for questions & comments:
mfrey@ieee.org